



~~IN THE UNITED STATES PATENT AND TRADEMARK OFFICE~~

28/7/7

In re Applicant:

Ofer DU-NOUR

Serial No.: 09/762,473

Filed: February 7, 2001

Group Art Unit: 2877

**For:** Method and Apparatus for Measuring the Thickness of a Transparent Film, Particularly of a Photoresist Film on a Semiconductor Substrate

Attorney  
Docket: **24982**  
Previously 1639/14

Examiner: Samuel A. Turner

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

**PETITION AND FEE FOR EXTENSION OF TIME UNDER 37 CFR 1.136(a)**

Sir:

- (1) This is a petition for an extension of time to respond to the Office Action mailed September 2, 2003, for a period of three months.

(2) Applicant is a:  
 small entity       verified statement attached  
                                  verified statement filed  
 other than small entity

(3)

Extension	Fee for small entity <u>small entity</u>	Fee for other than <u>small entity</u>
<input type="checkbox"/> one month	\$ 55	\$ 110
<input type="checkbox"/> two months	\$ 210	\$ 420
<input checked="" type="checkbox"/> <b>three months</b>	<b>\$ 475</b>	<b>\$ 950</b>
<input type="checkbox"/> four months	\$ 740	\$ 1480

(4) An amendment  is filed herewith  
                                  has been filed

(5) Please charge the extension fee and any other amount required to Deposit Account No. **50-1407**. A duplicate copy of this form is enclosed.

Respectfully submitted,

**Sol Sheinbein  
Registration No. 25,457**

Date: February 18, 2004

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